

Notice of References Cited	Application/Control No. 10/810,164		Applicant(s)/Patent Under Reexamination WU ET AL.	
	Examiner Srirama Channavajjala		Art Unit 2166	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0055941	05-2002	Kolodner et al.	707/200
*	B	US-6,567,905	05-2003	Otis, Allen J.	711/170
*	C	US-6,324,631	11-2001	Kuiper, Kean Gerome	711/170
*	D	US-2006/0173939	08-2006	Yin et al.	707/206
*	E	US-2006/0031810	02-2006	Peng et al.	717/100
*	F	US-2005/0246402	11-2005	Wu et al.	707/205
*	G	US-7,089,273	08-2006	Wu et al.	707/206
*	H	US-6,317,869	11-2001	Adl-Tabatabai et al.	717/132
*	I	US-6,093,216	07-2000	Adl-Tabatabai et al.	717/128
*	J	US-5,699,539	12-1997	Garber et al.	711/2
*	K	US-6,560,619	05-2003	Flood et al.	707/206
*	L	US-6,339,779	01-2002	Houldsworth, Richard J.	707/206
*	M	US-6,622,226	09-2003	Dussud, Patrick H.	711/159

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 2005013134	02-2005	PCT	Gansha,Wu et al.	12/02
	O	WO 00/60468	10-2000	PCT	Houldsworth,Richard	12/02
	P	WO 01/73556	10-2001	PCT	Hayward,Andrew	12/02
	Q					
	R					
	S					
	T					

PAP
4/6/07

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Katherine Barabash et al. "Mostly accurate stack scanning", proceedings of the Java virtual machine research and technology symposium (JVM'01), 2001,
	V	Qian Yang et al. "java virtual machine timing probes: a study of object life span and garbage collection", IEEE Internation performance, computing, and communications conference, 2002, pp 73080
	W	Michal ciemiak et al. "open runtime platform: flexibility with performance using interfaces", JGI'02, Nov 2002, pp 156-164
	X	Christian Wirth, "incremental garbage collection: the basic algorithms", Jan, 2006, pp 1-16

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.